

ICS 77.140.20
CCS H40

SN

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

SN/T 3348-2012

**Determination of silicon, manganese, phosphorus, chromium,
nickel and tungsten in chrome-nickel-tungsten steel.
Wave-length dispersive X-ray fluorescence spectrometry
(English Translation)**

Issued on: December 12, 2012

Implemented on: July 1, 2013

Issued by: General Administration of Customs

Table of Contents

- Foreword
- 1 Scope
- 2 Normative references
- 3 Method summary
- 4 Reagents and materials
- 5 Instruments

Foreword

This standard was drafted in accordance with GB/T 1.1-2009 given rules.

This standard is proposed and managed by the National Certification and Accreditation Administration Committee.

This standard was drafted. People's Republic of China Shandong CIQ.

1 Scope

This standard specifies the chromium-nickel steel tungsten silicon, manganese, phosphorus, chromium, nickel, tungsten content of wavelength dispersive X-ray fluorescence spectrometric method.

This standard applies to the determination of chromium nickel-tungsten steel silicon, manganese, phosphorus, chromium, nickel, tungsten content in the measurement range shown in Table 1.

Table 1 Measuring range% (mass fraction)

Element measurement range measurement range of elements Silicon 0.069 to 0.41
Manganese 0.23 to 0.62 P 0.010 to 0.048 Chromium 0.30 to 1.93 Nickel 1.09 ~ 6.93
Tungsten, 0.60 to 1.60

2 Normative references

The following documents for the application of this document is essential. For dated references, only the dated version suitable for use herein Member. For undated references, the latest edition (including any amendments) applies to this document.

GB/T 1031 surface roughness parameters and their values GB/T 16597 metallurgical product analysis X-ray Fluorescence Spectrometry General

3 Method summary

Analysis of the sample surface processed into a smooth plane, at selected measuring instrument conditions, measure the X-ray characteristics of the analyte in the sample spectrum Ray fluorescence intensity, according to the quantitative relationship between X-ray fluorescence intensity between the analyte content, calculate the amount of analyte.

4 Reagents and materials

4.1

detector gas (P10). 90% argon, 10% methane for gas-flow proportional counter.

4.2

Standard sample. Spectroscopy using standard test block. Each element should be at least six standard samples, the content should be a certain interval, and covers the test element Pigment measurement range.

5 Instruments

5.1

wavelength dispersive X-ray fluorescence spectrometer, in line with GB/T 16597 regulations.

5.2

lathe, milling machine, planer, or other non-polluting metallographic sandpaper surface processing equipment.